

Notice of References Cited	Application/Control No. 10/821,701		Applicant(s)/Patent Under Reexamination MELIDEO, JOHN	
	Examiner JOSEPH T. PHAN		Art Unit 2614	Page 1 of 1

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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